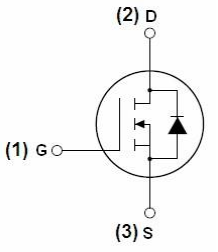
# AP50N03D

## 30V N-Channel Enhancement Mode MOSFET

### Description

The AP50N03D uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.






### General Features

$V_{DS}$ = 30V $I_D$ =50 A

$R_{DS(ON)}$ < 12mΩ @ $V_{GS}$=10V

### Application

Battery protection

Load switch

Uninterruptible power supply

### Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|---|---|---|---|
| AP50N03D | TO-252-3L | AP50N03D XXX YYYY | 2500 |

### Absolute Maximum Ratings ($T_C$=25℃unless otherwise noted)

| Symbol | Parameter | Rating | Units |
|---|---|---|---|
| $V_{DS}$ | Drain-Source Voltage | 30 | V |
| $V_{GS}$ | Gate-Source Voltage | ±20 | V |
| $I_D$@$T_C$=25℃ | Continuous Drain Current, $V_{GS}$ @ 10V[1] | 50 | A |
| $I_D$@$T_C$=100℃ | Continuous Drain Current, $V_{GS}$ @ 10V[1] | 30 | A |
| $I_D$@$T_A$=25℃ | Continuous Drain Current, $V_{GS}$ @ 10V[1] | 11 | A |
| $I_D$@$T_A$=70℃ | Continuous Drain Current, $V_{GS}$ @ 10V[1] | 9 | A |
| $I_{DM}$ | Pulsed Drain Current[2] | 112 | A |
| EAS | Single Pulse Avalanche Energy[3] | 24.2 | mJ |
| $I_{AS}$ | Avalanche Current | 22 | A |
| $P_D$@$T_C$=25℃ | Total Power Dissipation[4] | 37.5 | W |
| $P_D$@$T_A$=25℃ | Total Power Dissipation[4] | 2.42 | W |
| $T_{STG}$ | Storage Temperature Range | -55 to 175 | ℃ |
| $T_J$ | Operating Junction Temperature Range | -55 to 175 | ℃ |
| $R_{\theta JA}$ | Thermal Resistance Junction-Ambient [1] | 62 | ℃/W |
| $R_{\theta JC}$ | Thermal Resistance Junction-Case[1] | 4 | ℃/W |

Electrical Characteristics ($T_J$=25 °C, unless otherwise noted)

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|---|---|---|---|---|---|---|
| $BV_{DSS}$ | Drain-Source Breakdown Voltage | $V_{GS}$=0V , $I_D$=250uA | 30 | --- | --- | V |
| $\triangle BV_{DSS}/\triangle T_J$ | BVDSS Temperature Coefficient | Reference to 25°C , $I_D$=1mA | --- | 0.0193 | --- | V/°C |
| $R_{DS(ON)}$ | Static Drain-Source On-Resistance[2] | $V_{GS}$=10V , $I_D$=30A | --- | 9 | 12 | mΩ |
| | | $V_{GS}$=4.5V , $I_D$=15A | --- | 11 | 18 | |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{GS}$=$V_{DS}$ , $I_D$ =250uA | 1.2 | --- | 2.5 | V |
| $\triangle V_{GS(th)}$ | $V_{GS(th)}$ Temperature Coefficient | | --- | -3.97 | --- | mV/°C |
| $I_{DSS}$ | Drain-Source Leakage Current | $V_{DS}$=24V , $V_{GS}$=0V , $T_J$=25°C | --- | --- | 1 | uA |
| | | $V_{DS}$=24V , $V_{GS}$=0V , $T_J$=55°C | --- | --- | 5 | |
| $I_{GSS}$ | Gate-Source Leakage Current | $V_{GS}$=±20V , $V_{DS}$=0V | --- | --- | ±100 | nA |
| gfs | Forward Transconductance | $V_{DS}$=5V , $I_D$=30A | --- | 34 | --- | S |
| $R_g$ | Gate Resistance | $V_{DS}$=0V , $V_{GS}$=0V , f=1MHz | --- | 1.8 | --- | Ω |
| $Q_g$ | Total Gate Charge (4.5V) | $V_{DS}$=15V , $V_{GS}$=4.5V , $I_D$=15A | --- | 9.8 | --- | nC |
| $Q_{gs}$ | Gate-Source Charge | | --- | 4.2 | --- | |
| $Q_{gd}$ | Gate-Drain Charge | | --- | 3.6 | --- | |
| $T_{d(on)}$ | Turn-On Delay Time | $V_{DD}$=15V , $V_{GS}$=10V , $R_G$=3.3 $I_D$=15A | --- | 4 | --- | ns |
| $T_r$ | Rise Time | | --- | 8 | --- | |
| $T_{d(off)}$ | Turn-Off Delay Time | | --- | 31 | --- | |
| $T_f$ | Fall Time | | --- | 4 | --- | |
| $C_{iss}$ | Input Capacitance | $V_{DS}$=15V , $V_{GS}$=0V , f=1MHz | --- | 940 | --- | pF |
| $C_{oss}$ | Output Capacitance | | --- | 131 | --- | |
| $C_{rss}$ | Reverse Transfer Capacitance | | --- | 109 | --- | |
| $I_S$ | Continuous Source Current[1,5] | $V_G$=$V_D$=0V , Force Current | --- | --- | 43 | A |
| $I_{SM}$ | Pulsed Source Current[2,5] | | --- | --- | 112 | A |
| $V_{SD}$ | Diode Forward Voltage[2] | $V_{GS}$=0V , $I_S$=1A , $T_J$=25°C | --- | --- | 1 | V |
| $t_{rr}$ | Reverse Recovery Time | $I_F$=30A , dI/dt=100A/μs , $T_J$=25°C | --- | 8.5 | --- | nS |
| $Q_{rr}$ | Reverse Recovery Charge | | --- | 2.2 | --- | nC |

Note :

1 .The data tested by surface mounted on a 1 inch$^2$ FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width ≦ 300us , duty cycle ≦ 2%

3 .The EAS data shows Max. rating . The test condition is $V_{DD}$=25V,$V_{GS}$=10V,L=0.1mH,$I_{AS}$=22A

4.The power dissipation is limited by 175°C junction temperature

5.The data is theoretically the same as $I_D$ and $I_{DM}$ , in real applications , should be limited by total power dissipation.

## Typical Characteristics

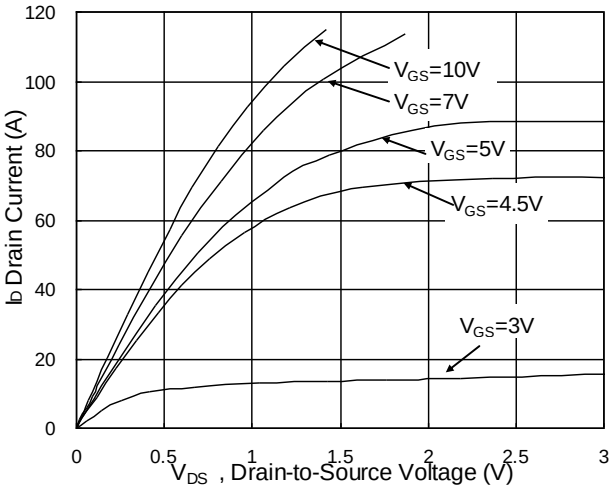



Fig.1 Typical Output Characteristics

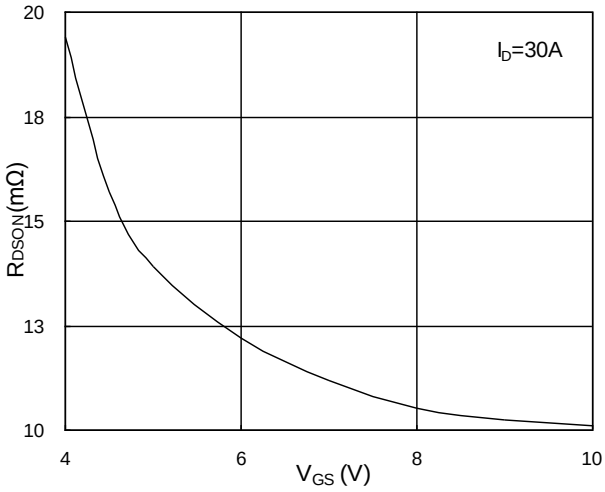



Fig.2 On-Resistance vs. G-S Voltage

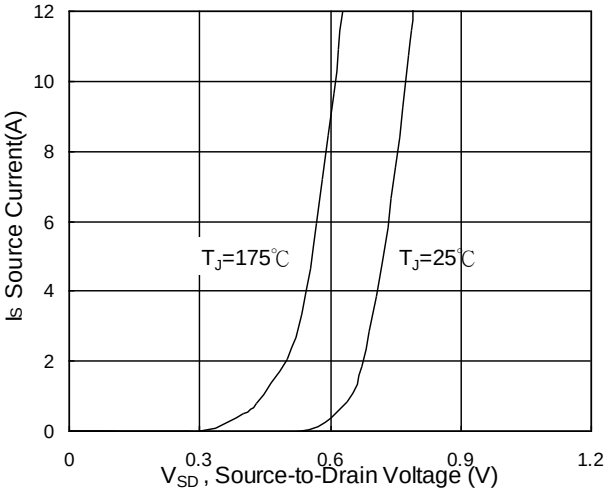



Fig.3 Forward Characteristics of Reverse

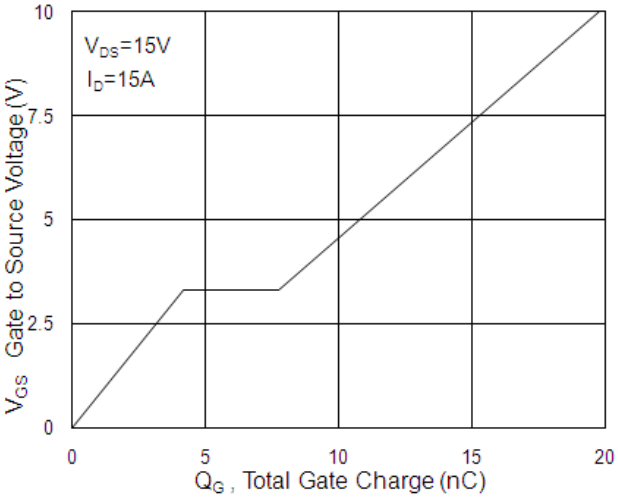



Fig.4 Gate-Charge Characteristics

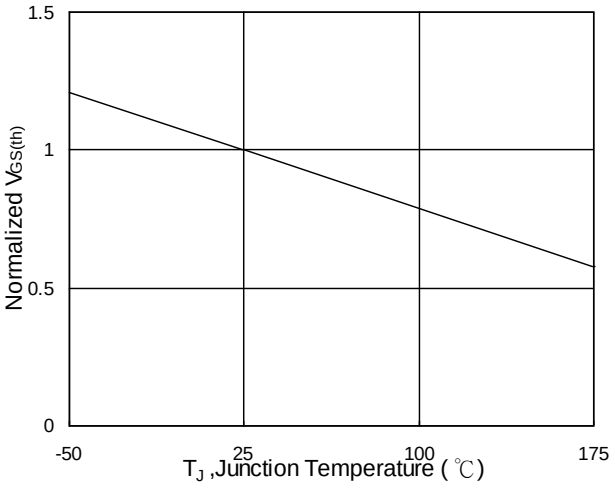



Fig.5 Normalized $V_{GS(th)}$ vs. $T_J$

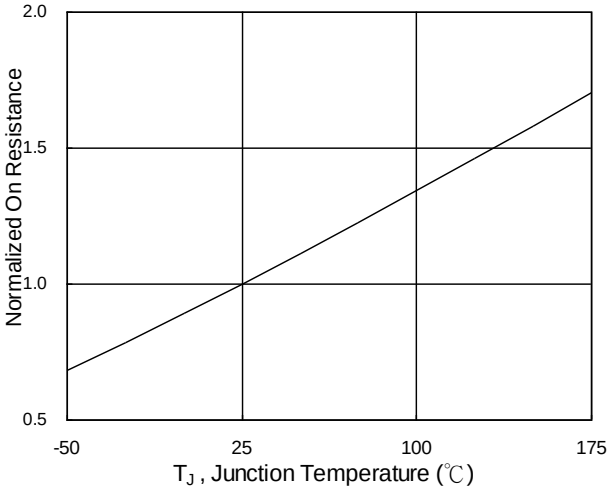



Fig.6 Normalized $R_{DSON}$ vs. $T_J$

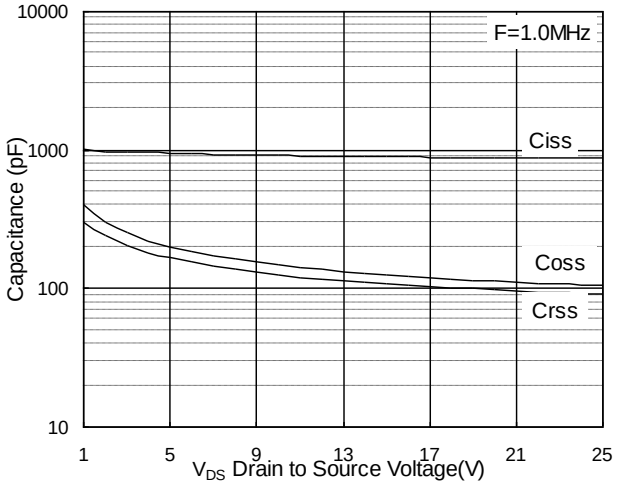



Fig.7 Capacitance

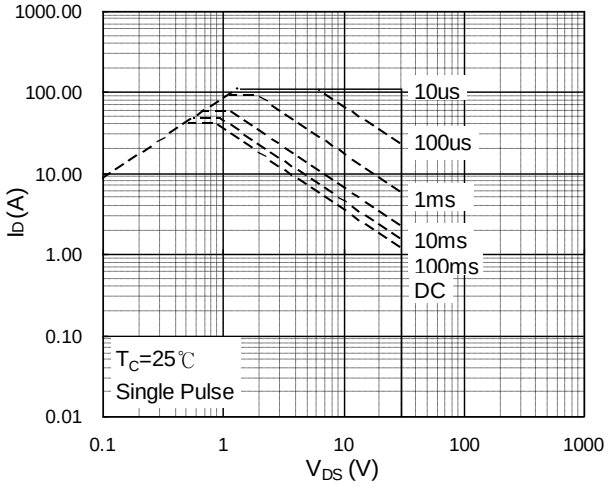



Fig.8 Safe Operating Area

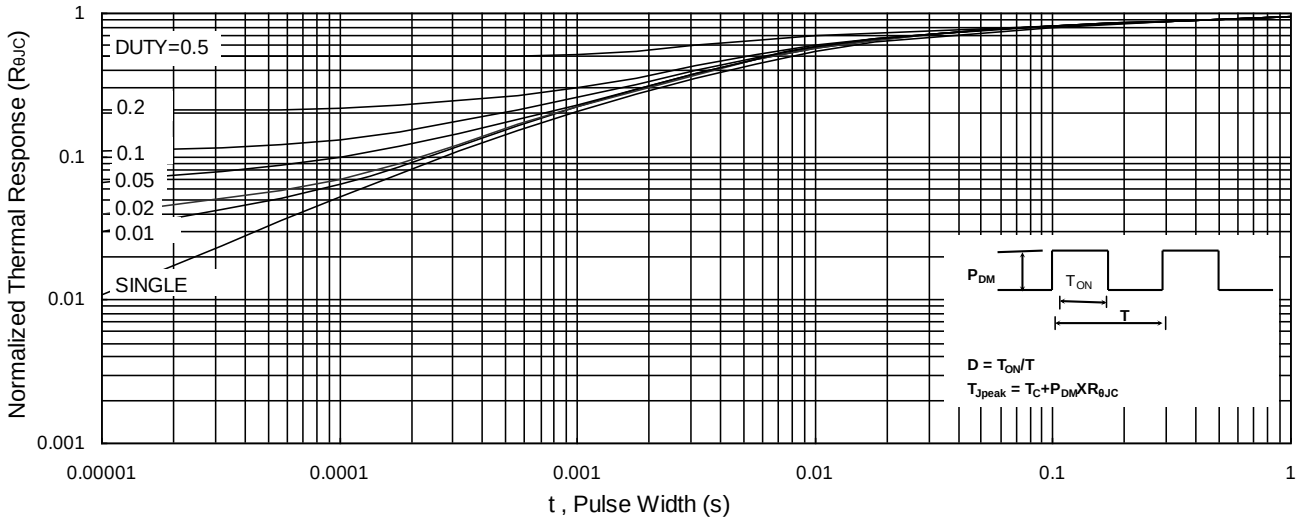



Fig.9 Normalized Maximum Transient Thermal Impedance

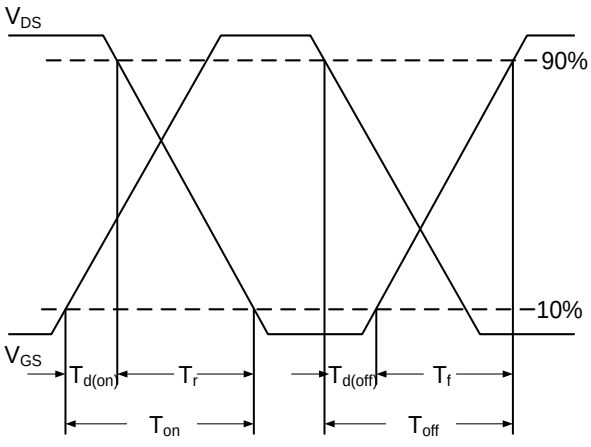



Fig.10 Switching Time Waveform

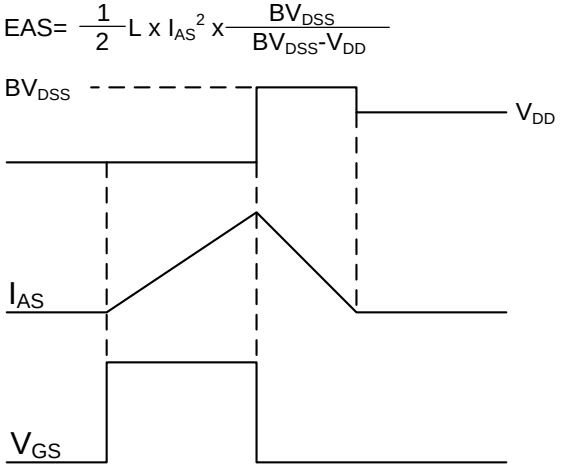
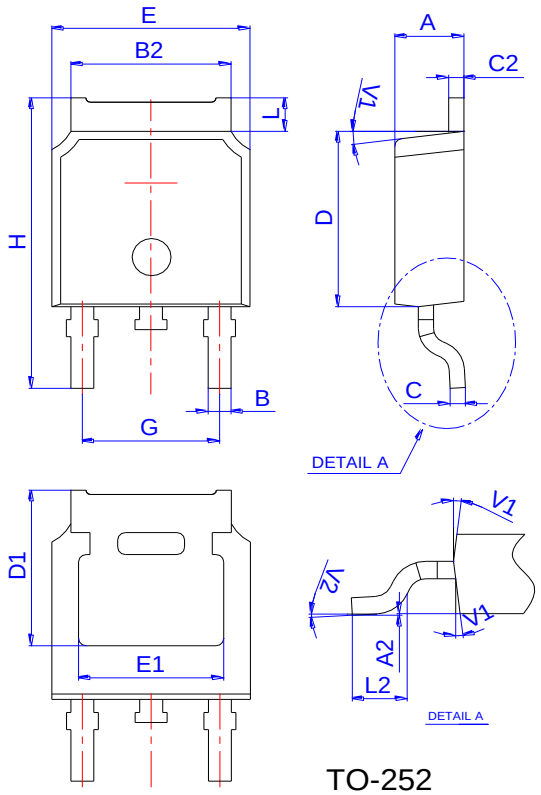



Fig.11 Unclamped Inductive Switching Waveform

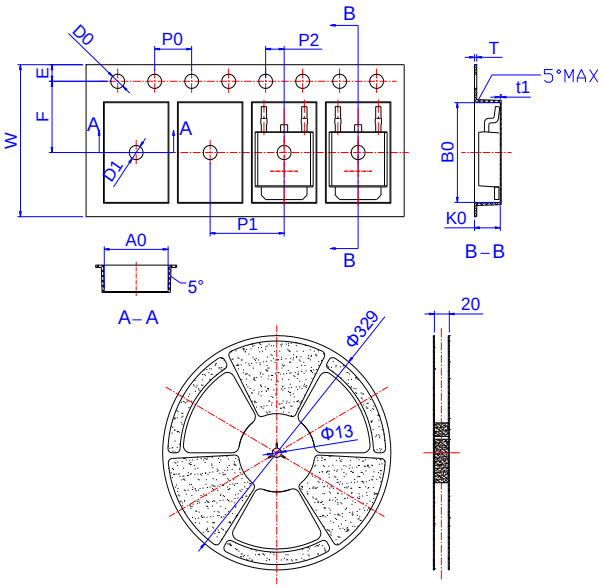
## Package Mechanical Data




TO-252

| Ref. | Dimensions | | | | | |
|---|---|---|---|---|---|---|
| | Millimeters | | | Inches | | |
| | Min. | Typ. | Max. | Min. | Typ. | Max. |
| A | 2.10 | | 2.50 | 0.083 | | 0.098 |
| A2 | 0 | | 0.10 | 0 | | 0.004 |
| B | 0.66 | | 0.86 | 0.026 | | 0.034 |
| B2 | 5.18 | | 5.48 | 0.202 | | 0.216 |
| C | 0.40 | | 0.60 | 0.016 | | 0.024 |
| C2 | 0.44 | | 0.58 | 0.017 | | 0.023 |
| D | 5.90 | | 6.30 | 0.232 | | 0.248 |
| D1 | 5.30REF | | | 0.209REF | | |
| E | 6.40 | | 6.80 | 0.252 | | 0.268 |
| E1 | 4.63 | | | 0.182 | | |
| G | 4.47 | | 4.67 | 0.176 | | 0.184 |
| H | 9.50 | | 10.70 | 0.374 | | 0.421 |
| L | 1.09 | | 1.21 | 0.043 | | 0.048 |
| L2 | 1.35 | | 1.65 | 0.053 | | 0.065 |
| V1 | | 7° | | | 7° | |
| V2 | 0° | | 6° | 0° | | 6° |

## Reel Specification-TO-252




| Ref. | Dimensions | | | | | |
|---|---|---|---|---|---|---|
| | Millimeters | | | Inches | | |
| | Min. | Typ. | Max. | Min. | Typ. | Max. |
| W | 15.90 | 16.00 | 16.10 | 0.626 | 0.630 | 0.634 |
| E | 1.65 | 1.75 | 1.85 | 0.065 | 0.069 | 0.073 |
| F | 7.40 | 7.50 | 7.60 | 0.291 | 0.295 | 0.299 |
| D0 | 1.40 | 1.50 | 1.60 | 0.055 | 0.059 | 0.063 |
| D1 | 1.40 | 1.50 | 1.60 | 0.055 | 0.059 | 0.063 |
| P0 | 3.90 | 4.00 | 4.10 | 0.154 | 0.157 | 0.161 |
| P1 | 7.90 | 8.00 | 8.10 | 0.311 | 0.315 | 0.319 |
| P2 | 1.90 | 2.00 | 2.10 | 0.075 | 0.079 | 0.083 |
| A0 | 6.85 | 6.90 | 7.00 | 0.270 | 0.271 | 0.276 |
| B0 | 10.45 | 10.50 | 10.60 | 0.411 | 0.413 | 0.417 |
| K0 | 2.68 | 2.78 | 2.88 | 0.105 | 0.109 | 0.113 |
| T | 0.24 | | 0.27 | 0.009 | | 0.011 |
| t1 | 0.10 | | | 0.004 | | |
| 10P0 | 39.80 | 40.00 | 40.20 | 1.567 | 1.575 | 1.583 |

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